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- ATPG systems
 - Methods to reduce test generation effort while generating efficient test vectors.
- Testability approximately measures:
 - Difficulty of setting circuit lines to 0 or 1.
 - Difficulty of observing internal circuit lines.
- Uses:
 - Analysis of difficulty of testing internal circuit parts.
 - Redesign circuit hardware or add special test hardware where measures show bad CY and OY.
 - Guidance for algorithms computing test patterns.
 - Estimation of test vector length.

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